

Form PTO-1449 U.S. Department of Commerce
(REV. 2-82) Patent and Trademark Office

Atty. Docket No.
36290/US/2 - 475387-00017

Serial No.
10/501,268

**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**
(Use several sheets if necessary)

Applicant(s)
Johannes F. de Boer et al.

Filing Date
July 9, 2004

Confirmation No.
7475

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| *Exam. Init. | | Document No. | | | | | | | Date | Name | Class | Subclass | Filing Date if Appropriate |
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Examiner

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| Form PTO-1449 U.S. Department of Commerce (REV. 2-82) Patent and Trademark Office | Atty. Docket No. 36290/US/2 – 475387-00017 | Serial No. 10/501,268 |
| INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary) | Applicant(s) Johannes F. de Boer et al. | |
| | Filing Date July 9, 2004 | Confirmation No. 7475 |

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